**All Times are in Mountain Standard Time (24-hour format)*

Time	Day 1: October 27, 2026
07:30 – 08:30	**Registration & Breakfast**
08:30 – 08:45	**Opening Remarks & Awards**
	PLENARY SESSION I Chair: Will Zortman – Sandia National Labs
08:45 – 09:15	**Keynote Talk I: Digital Twin Optimized Composable Systems - Enabling SOTA Intel Technologies in USG Systems** Dr. Carl E. McCants – Principal Engineer, Microelectronics SME | Intel Corporation
09:15 – 09:35	**Visionary Talk 1: Advanced Packaging for Photonics** Dr. Charles Woychik – VP Sales and Marketing | NHanced Semiconductors, Inc.
09:35 – 10:00	**Break**
	SESSION I: Invited Talks Chair: Mari-Therese Burton – ARMY
10:00 – 10:20	**METIS: Data Ecosystem for CHIPS Metrology** Dr. June Lau – Physicist and Data Specialist | NIST
10:20 – 10:40	**From Research to Impact: Technology, Talent & Teamwork in the SRC Ecosystem** Girish Wable – Director - Technical Program and Memberships | Semiconductor Research Corporation (SRC)
10:40 – 11:00	**Fast, Multi-Scale 3D X-Ray Inspection of Intact PCBs** Jeff Gelb – Director | Applied Materials, X-Ray Control Technologies

11:00 – 11:20	**Evaluation Approaches for Advanced Heterogeneous Packaging** Ruth Hidalgo-Hernandez – Technical Leader | DOD Aaron Clough-Paez – Technical Leader | DOD
11:20 – 11:40	**Evolving Technique and Application Challenges in Thermal Warpage Metrology** Neil Hubble – President | AkroMetrix, LLC
11:40 – 12:50	**Lunch**
	PLENARY SESSION II Chair: Dr. Adam Kimura – Battelle Memorial Institute
12:50 – 13:20	**Keynote Talk II: Beyond the Fab: Building Arizona's Semiconductor Talent and Partnership Pipeline** Dr. Kyle Squires – Senior Vice Provost of Engineering, Computing and Technology; Vice Provost of the Polytechnic Campus; Dean, Fulton Schools of Engineering | Arizona State University
	SESSION II: Panel Discussion Moderator: Dr. Wayne Churaman – CTEA Secure Edge/IoT, Microelectronics Commons
13:20 – 14:50	**Secure Edge** Daniel Marrujo – President and Managing Director | Trusted Strategic Solutions, LLC Tony Trinh – Senior Director, Advanced Concepts | Mercury Systems Dr. Yong Kim – AFRL Dr. Carl E. McCants – Principal Engineer, Microelectronics SME | Intel Corporation
14:50 – 15:10	**Break**
	SESSION III: Paper Presentations Chair: Dr. Calvin Chan – Sandia National Labs
15:10 – 15:30	**Quality Inspection of Printed Circuit Board Pin Insertion via Semantic Segmentation and Board-Level Feature Extraction** Nils Rabeneck – Technical University of Applied Sciences Regensburg

15:30 – 15:50	**PINN Framework for X-ray Laminography Inspection and Reconstruction** Shajib Ghosh – University of Florida
15:50 – 16:10	**Towards a framework for evaluating X-ray based volumetric image segmentation** Dr. Felix Kim – NIST
16:10 – 16:30	**PatchGuard Lacks Robustness: Breaking State-Of-The-Art Defect Detection Under New Norm Attacks** Kaleel Mahmood
16:30 – 17:30	**Exhibit & Poster Session**
17:30 – 19:30	**Social Event**

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Day 2: October 28, 2026

Time	
07:00 – 08:00	**Breakfast**
	PLENARY SESSION III Chair: Dr. Adam Waite – Battelle Memorial Institute
08:00 – 08:25	**Keynote Talk III: The Future of DoW Microelectronics** Eric Makara – Program Manager for Microelectronics | Office of the Under Secretary of War for Research and Engineering, OUSW(R&E)
08:25 – 08:50	**Keynote Talk IV: Enabling Massive Contour-Based Metrology in the Angstrom Era** Dr. Chih-Hung Max Hsieh – Senior Product Manager | Siemens EDA
	SESSION IV: Panel Discussion Moderator: David Via – Director of CONNECT Platform | Midwest Microelectronics Consortium (MMEC)
08:50 – 10:00	**Next-Gen Metrology & Inspection: Bridging NIST Science and Semiconductor Innovation** Dr. Jason Killgore – NIST Dr. Felix Kim – NIST Dr. Nathan Nakamura – NIST Dr. Marty Stevens – NIST Matt Walsh – Chief Engineer, Business Development Director | Florida Semiconductor Engine Dr. Eyal Weiss – Founder & CTO | Cybord
10:00 – 10:20	**Break**
	SESSION V: Invited Talks Chair: Christian Eakins – Air Force Research Lab

10:20 – 10:40	**Failure Observation and Reliability Evaluation via Scalable Imaging for Heterogeneous Technologies** Dr. Darren Crum – Director of Microelectronics Lab | Purdue Applied Research Institute
10:40 – 11:00	**Analog AI for Reliability** Dr. Rong Pan – Professor | School of Computing and Augmented Intelligence, Arizona State University
11:00 – 11:20	**Classification of Defects in Tomographic Reconstructions of Hyperscale Advanced Packages** Dr. Jacob D. Rezac – Mathematical Statistician | NIST
11:20 – 11:40	**Embedded Mixed Signal Test and Reliability Monitoring in Biomedical Electronics** Christian Gil Ramiscal – Technical Staff Engineer | Microchip Technology Inc. Krishna Pramod Madabhushi – Senior Principal IC Design Engineer | Medtronic
11:40 – 12:00	**Advances in Hyperspectral X-ray Imaging for Hardware Verification** Dr. Eric Goodman – Principal Member Technical Staff | Sandia National Laboratories
12:00 – 13:00	**Lunch**
	SESSION VI: Panel Discussion Moderator: Dr. Erin Gawron-Hyla – Protective Technologies Team Lead | DEVCOM Army Research Laboratory
13:00 – 14:30	**Microelectronics Workforce Development** Dr. Debbie Black-Conn – WFD Lead | ME Commons Dr. Marla L. Dowell – Executive Director, EDGE Consortium | Dartmouth College Ms. Alex Winslow – NNME Lead | SEMI Foundation Dr. Peggy Williams – Program Manager, SCALE Workforce Development Program | Naval Surface Warfare Center, Crane Division
	SESSION VII: Invited Talks (Short Session) Chair: Sneha Sudhakaran – Florida Institute of Technology

14:30 – 15:10	**Progress in Electrical Metrology for Conducted and Side Channel Measurements** Dr. Nelson Hastings – Cybersecurity and Privacy Applications Group | NIST Dr. Jim Booth – Guided Wave EM Group Leader | NIST
15:10 – 15:25	**Break**
	SESSION VIII: Paper Presentations Chair: Dr. Jacob D. Rezac – NIST
15:25 – 15:45	**Hardside: Pre-Silicon Side-Channel Analysis on Hardware AES with Deep Learning** Logan Reichling – University of Cincinnati
15:45 – 16:05	**Adams Bridge Accelerator: Bridging the Post-Quantum Transition** Mojtaba Bisheh-Niasa – Microsoft
16:05 – 16:25	**Using a CCFI Security Scheme on a RISC-V Core to Observe EMFI Effects and Establish Fault Models** Virgile Bouchon – Mines Saint-Etienne
16:25 – 16:45	**Side-Channel Assessment of Rijndael_256 Algorithm** Loic Djomo Tchuenkou – Morgan State University
16:45 – 17:00	**Break**
	SESSION IX: Paper Presentations Chair: Michael Haselm – Sandia National Labs
17:00 – 17:20	**A Quantitative Framework for Microelectronics Assurance from Physical Inspection** Dr. Adam Kimura – Battelle Memorial Institute
17:20 – 17:40	**Reversing the Clock: Layout-Aware Recovery of Design Intent from Clock Distribution Networks** Sascha Tommasone – TechInsights Inc.

17:40 – 18:00	**A Telemetry-Guided DDR/GDDR Screening Framework for AI-Oriented Memory Systems** Cong Xu – University of South Florida	

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Time	Day 3: October 29, 2026
07:00 – 08:00	**Breakfast**
	PLENARY SESSION IV Chair: Dr. Kanad Basu
08:00 – 08:30	**Keynote Talk V: From Prototyping to Trust: Lifecycle Assurance for Advanced Heterogeneous Integration** Dr. Krishnendu Chakrabarty – Fulton Professor of Microelectronics | Arizona State University
08:30 – 08:50	**Break**
	SESSION X: Invited Talks Chair: Dr. Jason Killgore – NIST
08:50 – 09:10	**Attacking AI with AI: fault injection on edge NPU case study** Jasper van Woudenberg – Senior Principal Security Technologist | Keysight Technologies
09:10 – 09:30	**Multiphoton Microscopy - A New Metrology Tool** Dr. Khanh Kieu – Associate Professor of Optical Sciences | The University of Arizona
09:30 – 10:05	**IEEE P3164: Security Annotation for Electronic Design Integration (SA-EDI)** Dr. Matthew Areno – Co-Chair of Secure Edge | Midwest Microelectronics Consortium
10:05 – 10:25	**Break**

	SESSION XI: Paper Presentations Chair: Emily Haines – Battelle Memorial Institute
10:25 – 10:45	**Hide and Speak: Cross-Chiplet Covert Channel Attack in Heterogeneously Integrated Processors** Abir Akib – University of Maryland
10:45 – 11:05	**Temperature-Triggered Liquid-State Hardware Trojans for Denial-of-Service in a Plastic-Encapsulated Microcontroller** Parth Agarwal – University of Waterloo
11:05 – 11:25	**Symbolic Triage of Gate-Level Information-Flow Evidence for Hardware Trojan Analysis** Dhruvakumar Aklekar – University of North Carolina at Charlotte
11:25 – 11:45	**D2D-SLEUTH: S-Parameter Link Evaluation for Unauthorized Tap Hunting** Dan Fiumara – Rensselaer Polytechnic Institute
11:45 – 12:50	**Lunch**
	SESSION XII: Paper Presentations Chair: TJ Manno – Sandia National Labs
12:50 – 13:10	**PCB-QA: Evaluating LLMs over the First Printed Circuit Board Schematic Question-Answer Dataset** Sahana Srinivasan – UNSW Sydney
13:10 – 13:30	**Active RF Reflectometry and Machine Learning for Recycled Board Detection** Michael Hilt – University of Waterloo
13:30 – 13:50	**PCB-SAGE: LLM-Assisted Security Assessment with Grounded Evidence Across PCB Artifacts** Parsa Mirfasihi – University of Arizona
13:50 – 14:10	**Break**

SESSION XIII: Paper Presentations

Chair: Dr. Jim Booth – Guided Wave EM Group Leader | NIST

14:10 – 14:30	**Encryption using Physical Unclonable Functions** Nikolaos Mastorakis – Arizona State University
14:30 – 14:50	**Multi-Angle Specular Constellation Dots for Integrated Circuit Package Authentication** Paul Benedetto – Arizona State University
14:50 – 15:10	**MEW-QRC: Physically Unclonable Melt-Electrowritten Quick-Response Codes for Secure Authentication** Neelofar Hassan – New York University
15:10 – 15:30	**An AI-Empowered Multidisciplinary Approach to the Detection of Social Engineering Attacks** Joseph M. Hatfield – United States Naval Academy
15:30 – 15:50	**Converged Standardization: Improving Template Attack Success Using Aggregated Power Trace Self-Referencing** David Ingalls – Indiana University
15:50 – 16:00	**Closing Remarks**